

M5M417800AJ, TP-6, -7, -6S, -7S

FAST PAGE MODE 16777216-BIT (2097152-WORD BY 8-BIT) DYNAMIC RAM

DESCRIPTION

This is a family of 2097152-word by 8-bit dynamic RAMS, fabricated with the high performance CMOS process, and is ideal for large-capacity memory systems where high speed, low power dissipation, and low costs are essential.

The use of double-layer aluminum process combined with triple-well CMOS technology and a single-transistor dynamic storage stacked capacitor cell provide high circuit density at reduced costs. Multiplexed address inputs permit both a reduction in pins and an increase in system densities.

FEATURES

Type name	RAS access time (max.ns)	CAS access time (max.ns)	Address access time (max.ns)	OE access time (max.ns)	Cycle time (min.ns)	Power dissipation (typ.mW)
M5M417800AXX-6, -6S	60	15	30	15	110	540
M5M417800AXX-7, -7S	70	20	35	20	130	475

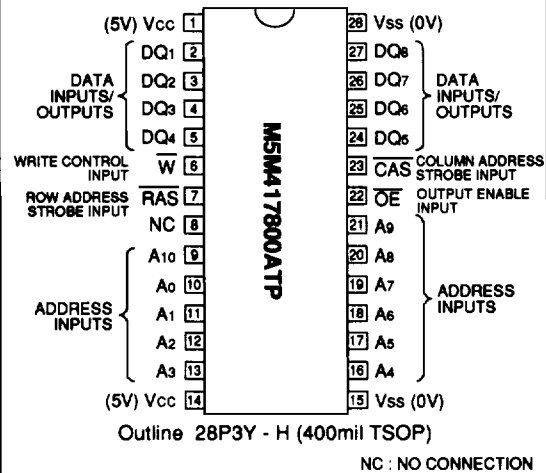
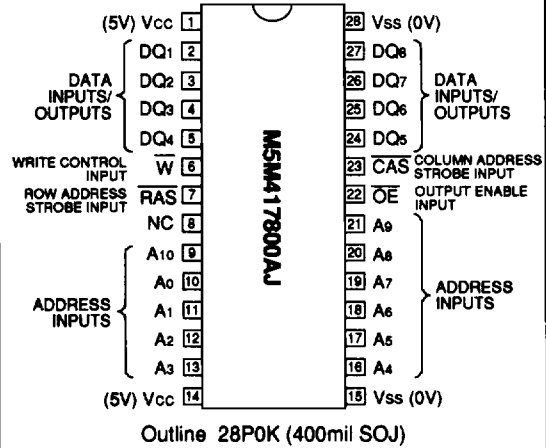
XX = J, TP

- Standard 28 pin SOJ, 28 pin TSOP
- Single 5V ± 10% supply
- Low stand-by power dissipation
 - 5.5mW (Max) CMOS Input level
 - 2.2mW*(Max) CMOS Input level
- Low operating power dissipation
 - M5M417800Axx-6, -6S 660.0mW (Max)
 - M5M417800Axx-7, -7S 580.0mW (Max)
- Self refresh capability*
 - self refresh current 400.0µA (Max)
- Fast-page mode, Read-modify-write, RAS-only refresh, CAS before RAS refresh, Hidden refresh capabilities
- Early-write mode and OE to control output buffer impedance
- All inputs, output TTL compatible and low capacitance
- 2048 refresh cycles every 32ms (A₀~A₁₀)
 - *Applicable to self refresh version (M5M417800AJ, TP-6S, -7S : option only)

APPLICATION

Main memory unit for computers, Microcomputer memory, Refresh memory for CRT

PIN CONFIGURATION (TOP VIEW)



FUNCTION

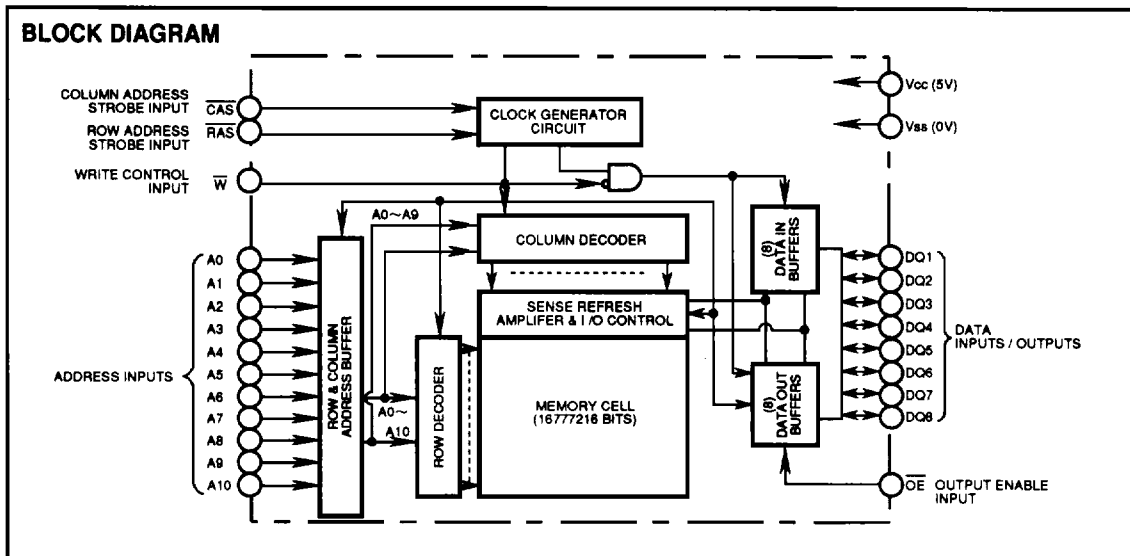
The M5M417800AJ, TP provide, in addition to normal read, write, and read-modify-write operations, a number of other

functions, e.g., fast page mode, $\overline{\text{RAS}}$ -only refresh, and delayed-write. The input conditions for each are shown in Table 1.

Table 1 Input conditions for each mode

Operation	Inputs						Input/Output		Refresh	Remark
	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{W}}$	$\overline{\text{OE}}$	Row address	Column address	Input	Output		
Read	ACT	ACT	NAC	ACT	APD	APD	OPN	VLD	YES	Fast page mode identical
Write (Early write)	ACT	ACT	ACT	DNC	APD	APD	VLD	OPN	YES	
Write (Delayed write)	ACT	ACT	ACT	DNC	APD	APD	VLD	IVD	YES	
Read-modify-write	ACT	ACT	ACT	ACT	APD	APD	VLD	VLD	YES	
$\overline{\text{RAS}}$ -only refresh	ACT	NAC	DNC	DNC	APD	DNC	DNC	OPN	YES	
Hidden refresh	ACT	ACT	DNC	ACT	APD	DNC	OPN	VLD	YES	
Self refresh	ACT	ACT	DNC	DNC	DNC	DNC	DNC	OPN	YES	
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh	ACT	ACT	NAC	DNC	DNC	DNC	DNC	OPN	YES	
Standby	NAC	DNC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note : ACT : active, NAC : nonactive, DNC : don't care, VLD : valid, IVD : invalid, APD : applied, OPN : open



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
Vcc	Supply voltage	With respect to Vss	-1~7	V
Vi	Input voltage		-1~7	V
Vo	Output voltage		-1~7	V
Io	Output current		50	mA
Pd	Power dissipation	Ta = 25°C	1000	mW
Topr	Operating temperature		0~70	°C
Tstg	Storage temperature		-65~150	°C

RECOMMENDED OPERATING CONDITIONS (Ta = 0~70°C, unless otherwise noted) (Note 1)

Symbol	Parameter	Limits			Unit
		Min	Nom	Max	
Vcc	Supply voltage	4.5	5	5.5	V
Vss	Supply voltage	0	0	0	V
Vih	High-level input voltage, all inputs	2.4		6.0	V
Vil	Low-level input voltage, all inputs	-1.0		0.8	V

Note 1 : All voltage values are with respect to Vss

ELECTRICAL CHARACTERISTICS (Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
Voh	High-level output voltage	Ioh = -5mA	2.4		Vcc	V
Vol	Low-level output voltage	Iol = 4.2mA	0		0.4	V
Ioz	Off-state output current	Q floating 0V ≤ Vout ≤ 5.5V	-10		10	μA
Ii	Input current	0V ≤ Vin ≤ 6.5V, Other inputs pins = 0V	-10		10	μA
Icc1 (AV)	Average supply current from Vcc operating (Note 3,4)	M5M417800A-6,-6S	RAS, CAS cycling trc = twc = min. output open		120	mA
		M5M417800A-7,-7S			105	
Icc2	Supply current from Vcc, stand-by	RAS = CAS = Vih, output open		2	mA	
		RAS = CAS ≥ Vcc - 0.5		1		
Icc3 (AV)	Average supply current from Vcc refreshing (Note 3)	M5M417800A-6,-6S	RAS cycling, CAS = Vih trc = min. output open		120	mA
		M5M417800A-7,-7S			105	
Icc4 (AV)	Average supply current from Vcc Fast-Page-Mode (Note 3,4)	M5M417800A-6,-6S	RAS = Vil, CAS cycling trc = min. output open		70	mA
		M5M417800A-7,-7S			60	
Icc6 (AV)	Average supply current from Vcc CAS before RAS refresh mode (Note 3)	M5M417800A-6,-6S	CAS before RAS refresh cycling trc = min. output open		120	mA
		M5M417800A-7,-7S			105	

Note 2: Current flowing into an IC is positive, out is negative.

3: Icc1 (AV), Icc3 (AV), Icc4 (AV) and Icc6 (AV) are dependent on cycle rate. Maximum current is measured at the fastest cycle rate.

4: Icc1 (AV) and Icc4 (AV) are dependent on output loading. Specified values are obtained with the output open.

CAPACITANCE (Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
CI(A)	Input capacitance, address inputs	Vi = Vss f = 1MHz Vi = 25mVrms			5	pF
CI(OE)	Input capacitance, OE input				7	pF
CI(W)	Input capacitance, write control input				7	pF
CI(RAS)	Input capacitance, RAS input				7	pF
CI(CAS)	Input capacitance, CAS input				7	pF
CI/O	Input/Output capacitance, data ports				8	pF

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SWITCHING CHARACTERISTICS (Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted, see notes 5,12,13)

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
tCAC	Access time from $\overline{\text{CAS}}$ (Note 6,7)		15		20	ns
tRAC	Access time from $\overline{\text{RAS}}$ (Note 6,8)		60		70	ns
tAA	Column address access time (Note 6,9)		30		35	ns
tCPA	Access time from $\overline{\text{CAS}}$ precharge (Note 6,10)		35		40	ns
tOEA	Access time from $\overline{\text{OE}}$ (Note 6)		15		20	ns
tCLZ	Output low impedance time from $\overline{\text{CAS}}$ low (Note 6)	5		5		ns
tOFF	Output disable time after $\overline{\text{CAS}}$ high (Note 11)	0	15	0	15	ns
tOEZ	Output disable time after $\overline{\text{OE}}$ high (Note 11)	0	15	0	15	ns

Note 5 : An initial pause of 500 μ s is required after power-up followed by a minimum of eight initialization cycles (any combination of cycles containing a $\overline{\text{RAS}}$ clock such as $\overline{\text{RAS}}$ -Only refresh).

Note the $\overline{\text{RAS}}$ may be cycled during the initial pause. And any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles are required after prolonged periods (greater than 32 ms) of $\overline{\text{RAS}}$ inactivity before proper device operation is achieved.

6 : Measured with a load circuit equivalent to 2TTL loads and 100pF.

7 : Assumes that $t_{\text{RCO}} \geq t_{\text{RCO}}(\text{max})$ and $t_{\text{ASC}} \geq t_{\text{ASC}}(\text{max})$.

8 : Assumes that $t_{\text{RCO}} \leq t_{\text{RCO}}(\text{max})$ and $t_{\text{RAD}} \leq t_{\text{RAD}}(\text{max})$. If t_{RCO} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} will increase by amount that t_{RCO} exceeds the value shown.

9 : Assumes that $t_{\text{RAD}} \geq t_{\text{RAD}}(\text{max})$ and $t_{\text{ASC}} \leq t_{\text{ASC}}(\text{max})$.

10 : Assumes that $t_{\text{CP}} \leq t_{\text{CP}}(\text{max})$ and $t_{\text{ASC}} \geq t_{\text{ASC}}(\text{max})$.

11 : $t_{\text{OFF}}(\text{max})$ and $t_{\text{OEZ}}(\text{max})$ defines the time at which the output achieves the high impedance state ($I_{\text{out}} \leq \pm 10 \mu\text{A}$) and is not reference to $V_{\text{OH}}(\text{min})$ or $V_{\text{OL}}(\text{max})$.

TIMING REQUIREMENTS (For Read, Write, Read-Modify-Write, Refresh, and Fast-Page Mode Cycles)

(Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted See notes 12,13)

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
tREF	Refresh cycle time		32		32	ms
tRP	$\overline{\text{RAS}}$ high pulse width	40		50		ns
tRCD	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{CAS}}$ low (Note14)	20	45	20	50	ns
tCRP	Delay time, $\overline{\text{CAS}}$ high to $\overline{\text{RAS}}$ low	10		10		ns
tRPC	Delay time, $\overline{\text{RAS}}$ high to $\overline{\text{CAS}}$ low	0		0		ns
tCPN	$\overline{\text{CAS}}$ high pulse width	10		10		ns
tRAD	Column address delay time from $\overline{\text{RAS}}$ low (Note15)	15	30	15	35	ns
tASR	Row address setup time before $\overline{\text{RAS}}$ low	0		0		ns
tASC	Column address setup time before $\overline{\text{CAS}}$ low (Note16)	0	10	0	10	ns
tRAH	Row address hold time after $\overline{\text{RAS}}$ low	10		10		ns
tCAH	Column address hold time after $\overline{\text{CAS}}$ low	15		15		ns
tdzc	Delay time, data to $\overline{\text{CAS}}$ low (Note17)	0		0		ns
tdzo	Delay time, data to $\overline{\text{OE}}$ low (Note17)	0		0		ns
tcdd	Delay time, $\overline{\text{CAS}}$ high to data (Note18)	15		15		ns
tood	Delay time, $\overline{\text{OE}}$ high to data (Note18)	15		15		ns
tT	Transition time (Note19)	1	50	1	50	ns

Note 12 : The timing requirements are assumed $t_{\text{T}} = 5\text{ns}$.

13 : $V_{\text{IH}}(\text{min})$ and $V_{\text{IL}}(\text{max})$ are reference levels for measuring timing of input signals.

14 : $t_{\text{RCD}}(\text{max})$ is specified as a reference point only. If t_{RCD} is less than $t_{\text{RCD}}(\text{max})$, access time is t_{RAC} . If t_{RCD} is greater than $t_{\text{RCD}}(\text{max})$, access time is controlled exclusively by t_{CAC} or t_{AA} . $t_{\text{RCD}}(\text{min})$ is specified as $t_{\text{RCD}}(\text{min}) = t_{\text{RAH}}(\text{min}) + 2t_{\text{H}} + t_{\text{ASC}}(\text{min})$.

15 : $t_{\text{RAD}}(\text{max})$ is specified as a reference point only. If $t_{\text{RAD}} \geq t_{\text{RAD}}(\text{max})$ and $t_{\text{ASC}} \leq t_{\text{ASC}}(\text{max})$, access time is controlled exclusively by t_{AA} .

16 : $t_{\text{ASC}}(\text{max})$ is specified as a reference point only. If $t_{\text{RCD}} \geq t_{\text{RCD}}(\text{max})$ and $t_{\text{ASC}} \geq t_{\text{ASC}}(\text{max})$, access time is controlled exclusively by t_{CAC} .

17 : Either t_{dzc} or t_{dzo} must be satisfied.

18 : Either t_{cdd} or t_{ood} must be satisfied.

19 : t_{T} is measured between $V_{\text{IH}}(\text{min})$ and $V_{\text{IL}}(\text{max})$.

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Read and Refresh Cycles

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
trc	Read cycle time	110		130		ns
trās	RAS low pulse width	60	10000	70	10000	ns
tcās	CAS low pulse width	15	10000	20	10000	ns
tcsh	CAS hold time after RAS low	60		70		ns
trsh	RAS hold time after CAS low	15		20		ns
trcs	Read Setup time after CAS high	0		0		ns
trch	Read hold time after CAS low (Note 20)	0		0		ns
trrh	Read hold time after RAS low (Note 20)	10		10		ns
tral	Column address to RAS hold time	30		35		ns
toch	CAS hold time after OE low	15		20		ns
torh	RAS hold time after OE low	15		20		ns

Note 20 : Either trch or trrh must be satisfied for a read cycle.

Write Cycle (Early Write and Delayed Write)

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
twc	Write cycle time	110		130		ns
trās	RAS low pulse width	60	10000	70	10000	ns
tcās	CAS low pulse width	15	10000	20	10000	ns
tcsh	CAS hold time after RAS low	60		70		ns
trsh	RAS hold time after CAS low	15		20		ns
twcs	Write setup time before CAS low (Note 22)	0		0		ns
twch	Write hold time after CAS low	10		10		ns
tcwl	CAS hold time after W low	15		20		ns
trwl	RAS hold time after W low	15		20		ns
twp	Write pulse width	10		10		ns
tds	Data setup time before CAS low or W low	0		0		ns
tdh	Data hold time after CAS low or W low	10		15		ns
toeh	OE hold time after W low	15		20		ns

Read-Write and Read-Modify-Write Cycles

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
trwc	Read write/read modify write cycle time (Note21)	155		180		ns
tr _{AS}	RAS low pulse width	105	10000	120	10000	ns
tc _{AS}	CAS low pulse width	60	10000	70	10000	ns
tc _{SH}	CAS hold time after RAS low	105		120		ns
tr _{SH}	RAS hold time after CAS low	60		70		ns
tr _{CS}	Read setup time before CAS low	0		0		ns
tc _{WD}	Delay time, CAS low to W low (Note22)	40		45		ns
tr _{WD}	Delay time, RAS low to W low (Note22)	85		95		ns
t _{AWD}	Delay time, address to W low (Note22)	55		60		ns
tc _{WL}	CAS hold time after W low	15		20		ns
tr _{WL}	RAS hold time after W low	15		20		ns
t _{WP}	Write pulse width	10		10		ns
t _{DS}	Data setup time before W low	0		0		ns
t _{DH}	Data hold time after W low	10		15		ns
t _{OEH}	OE hold time after W low	15		15		ns

Note 21 : trwc is specified as trwc (min) = trac (max) + t_{ODD} (min) + trwl (min) + trp (min) + 5tr.

22 : twcs, tc_{WD}, tr_{WD} and t_{AWD} and, tc_{PWD} are specified as reference points only. If twcs ≥ twcs (min) the cycle is an early write cycle and the DQ pins will remain high impedance throughout the entire cycle. If tc_{WD} ≥ tc_{WD}(min), tr_{WD} ≥ tr_{WD} (min), t_{AWD} ≥ t_{AWD} (min) and tc_{PWD} ≥ tc_{PWD} (min) (for fast page mode cycle only), the cycle is a read-modify-write cycle and the DQ will contain the data read from the selected address. If neither of the above condition (delayed write) of the DQ (at access time and until CAS or OE goes back to VIH) is indeterminate.

Fast-Page Mode Cycle (Read, Early Write, Read -Write, Read-Modify-Write Cycle) (Note 23)

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
t _{PC}	Fast page mode read/write cycle time	40		45		ns
t _{PRWC}	Fast page mode read write/read modify write cycle time	85		95		ns
tr _{AS}	RAS low pulse width for read write cycle (Note24)	100	125000	115	125000	ns
t _{CP}	CAS high pulse width (Note25)	10	15	10	15	ns
tc _{PRH}	RAS hold time after CAS precharge	35		40		ns
tc _{PWD}	Delay time, CAS precharge to W low (Note22)	60		65		ns

Note 23 : All previously specified timing requirements and switching characteristics are applicable to their respective fast page mode cycle.

24 : tr_{AS} (min) is specified as two cycles of CAS input are performed.

25 : t_{CP} (max) is specified as a reference point only.

CAS before RAS Refresh Cycle (Note 26)

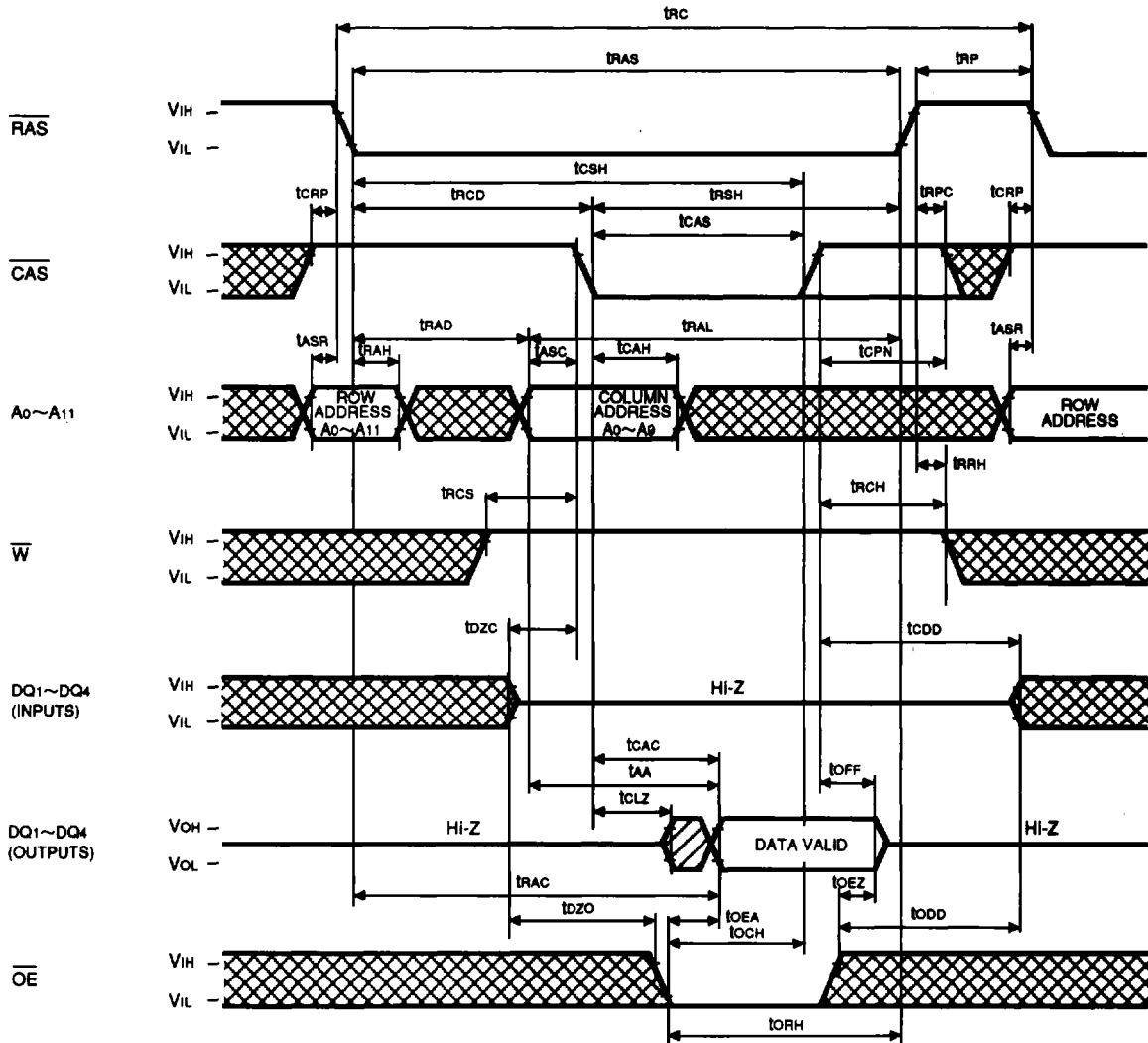
Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
tc _{SR}	CAS setup time before RAS low	10		10		ns
tc _{HR}	CAS hold time after RAS low	10		15		ns
tr _{SR}	Read setup time before RAS low	10		10		ns
tr _{HR}	Read hold time after RAS low	10		15		ns



Note 26 : Eight or more CAS before RAS cycles instead of eight RAS cycles are necessary for proper operation of CAS before RAS refresh mode.

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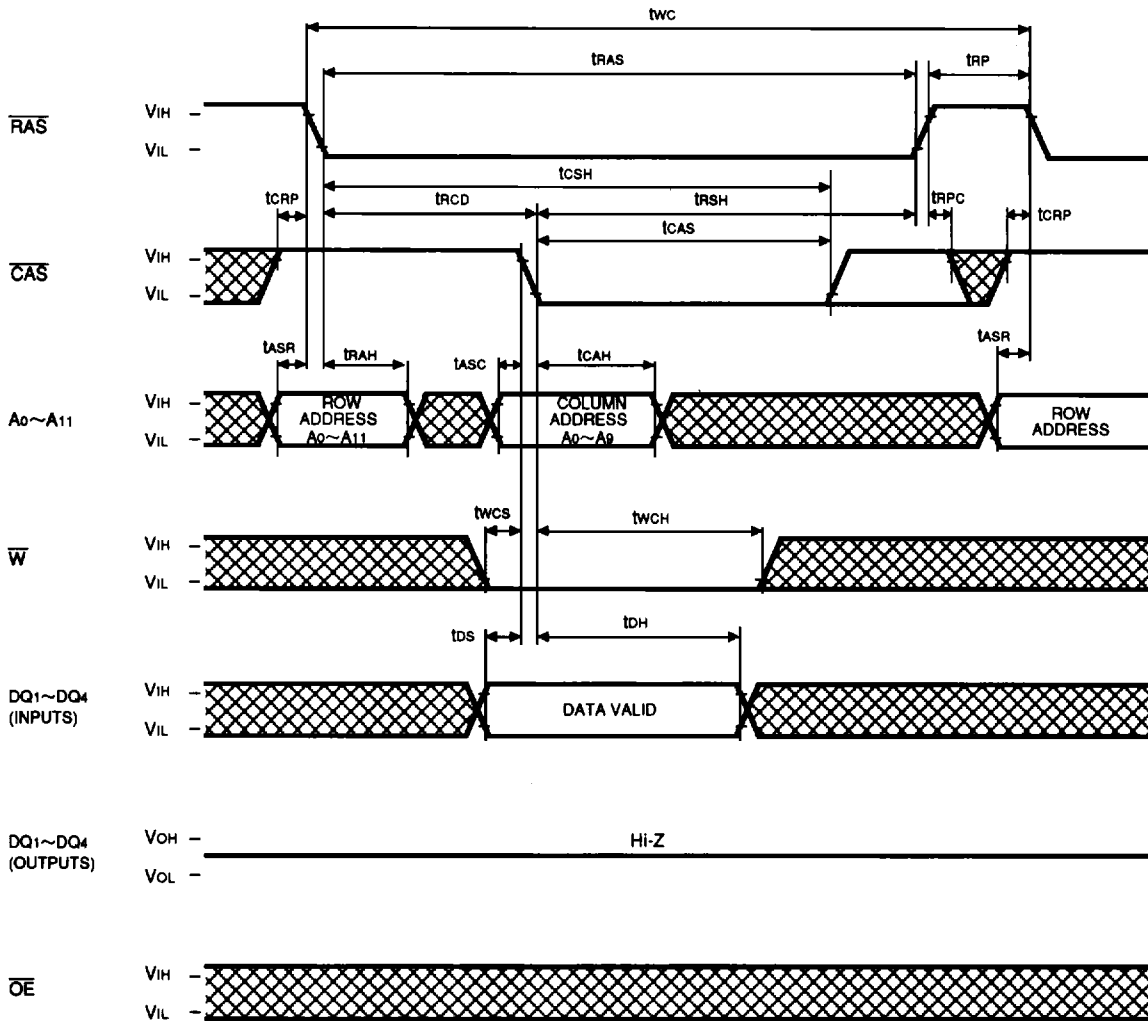
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Timing Diagrams (Note 27)
Read Cycle

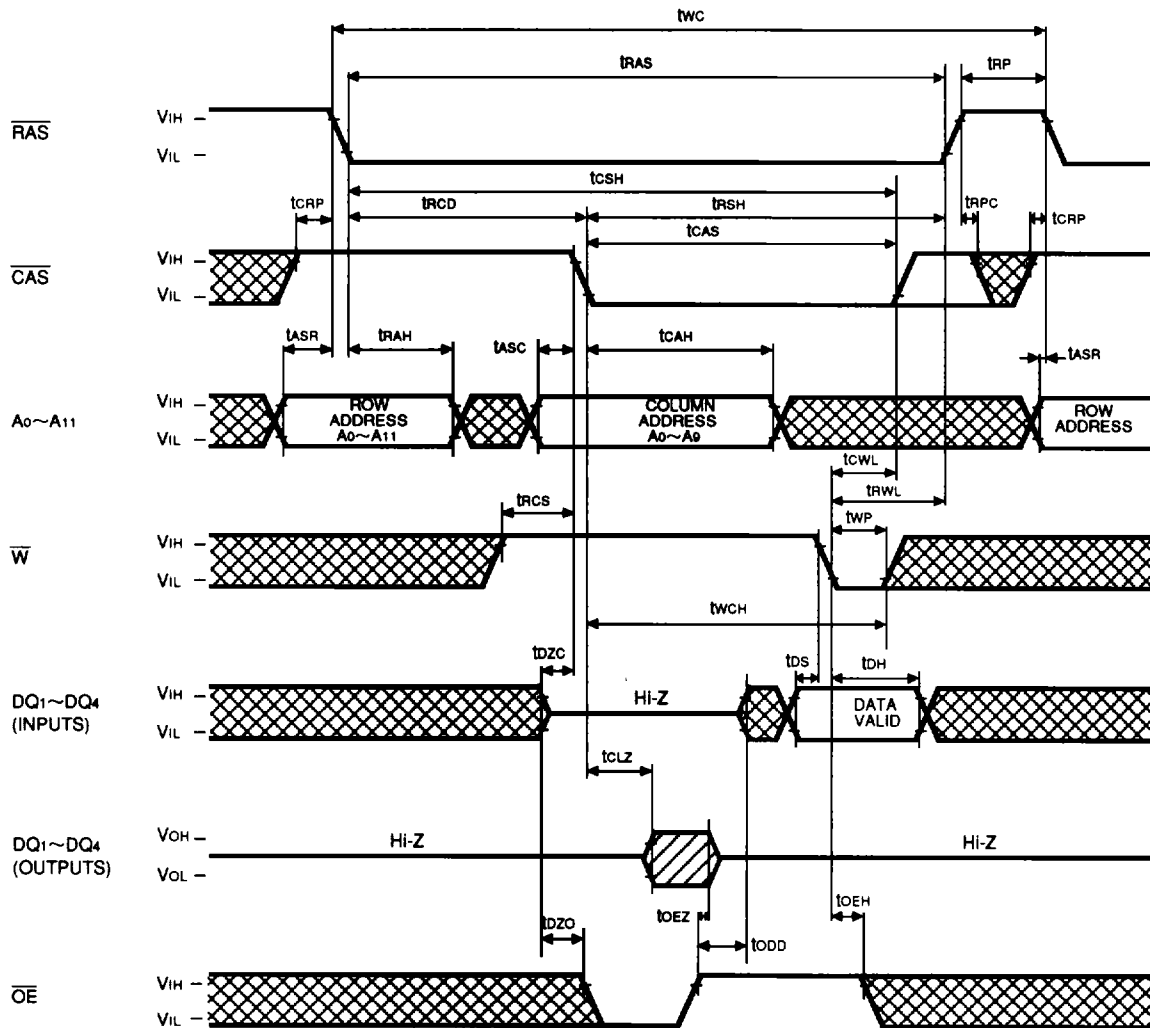


Note 27  Indicates the don't care input.
 $V_{IH(min)} \leq V_{IN} \leq V_{IH(max)}$ or $V_{IL(min)} \leq V_{IN} \leq V_{IL(max)}$
 Indicates the invalid output.

Write Cycle (Early write)



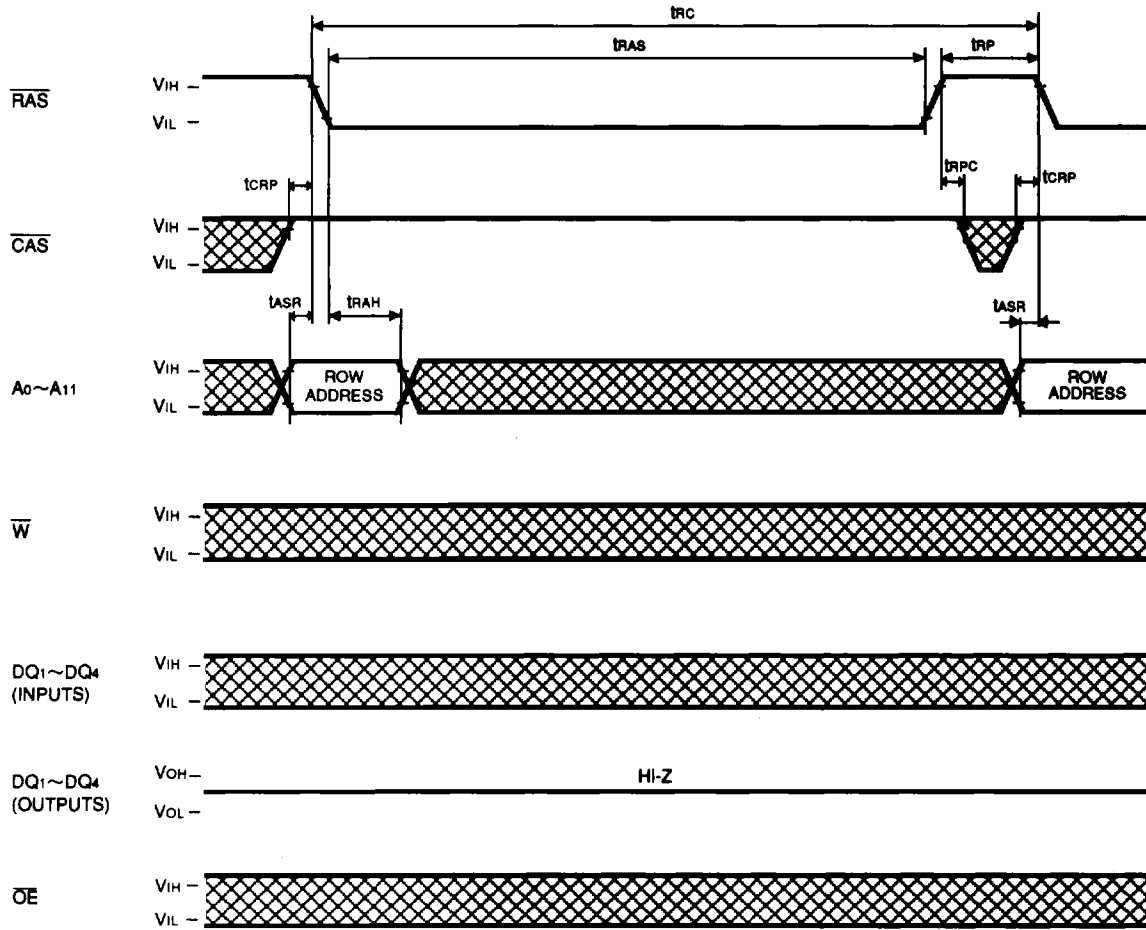
Write Cycle (Delayed write)



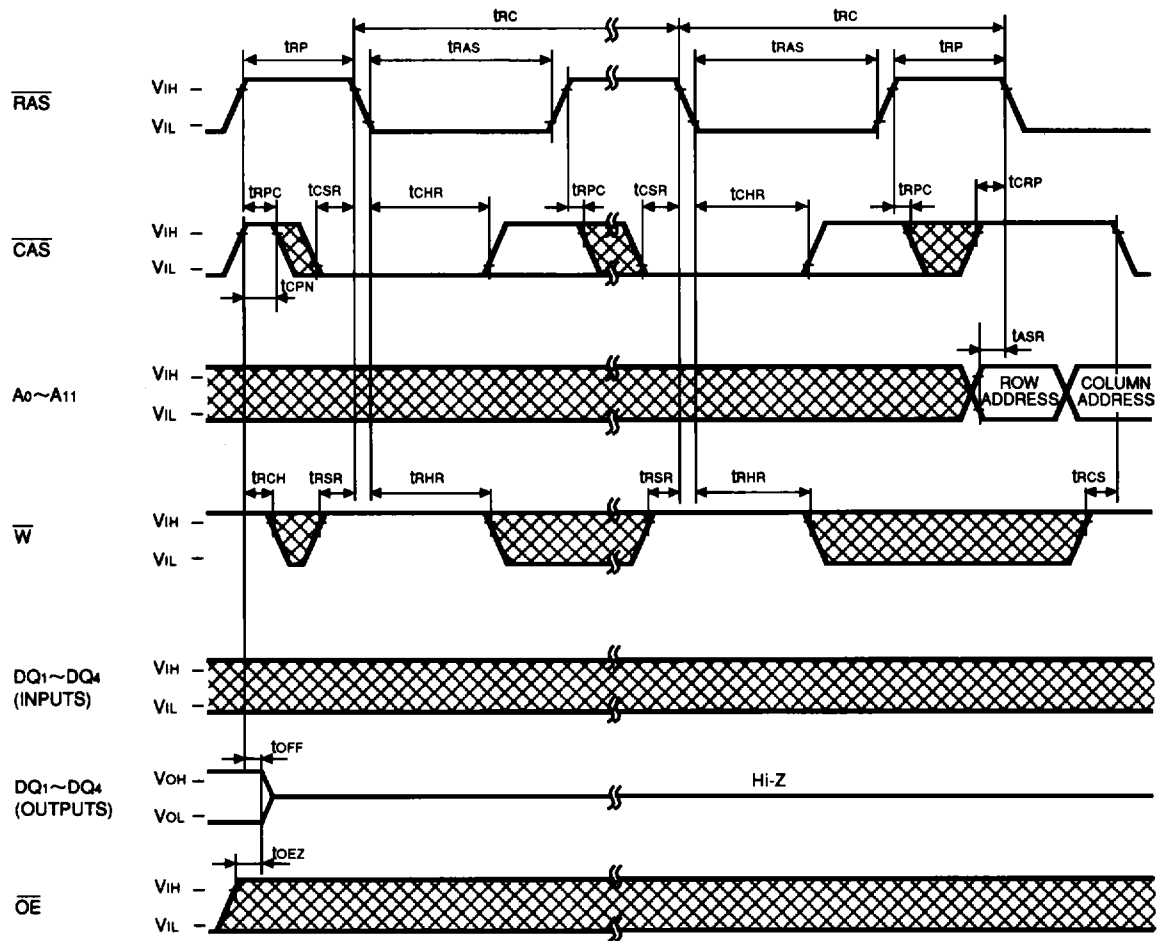
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RAS-only Refresh Cycle



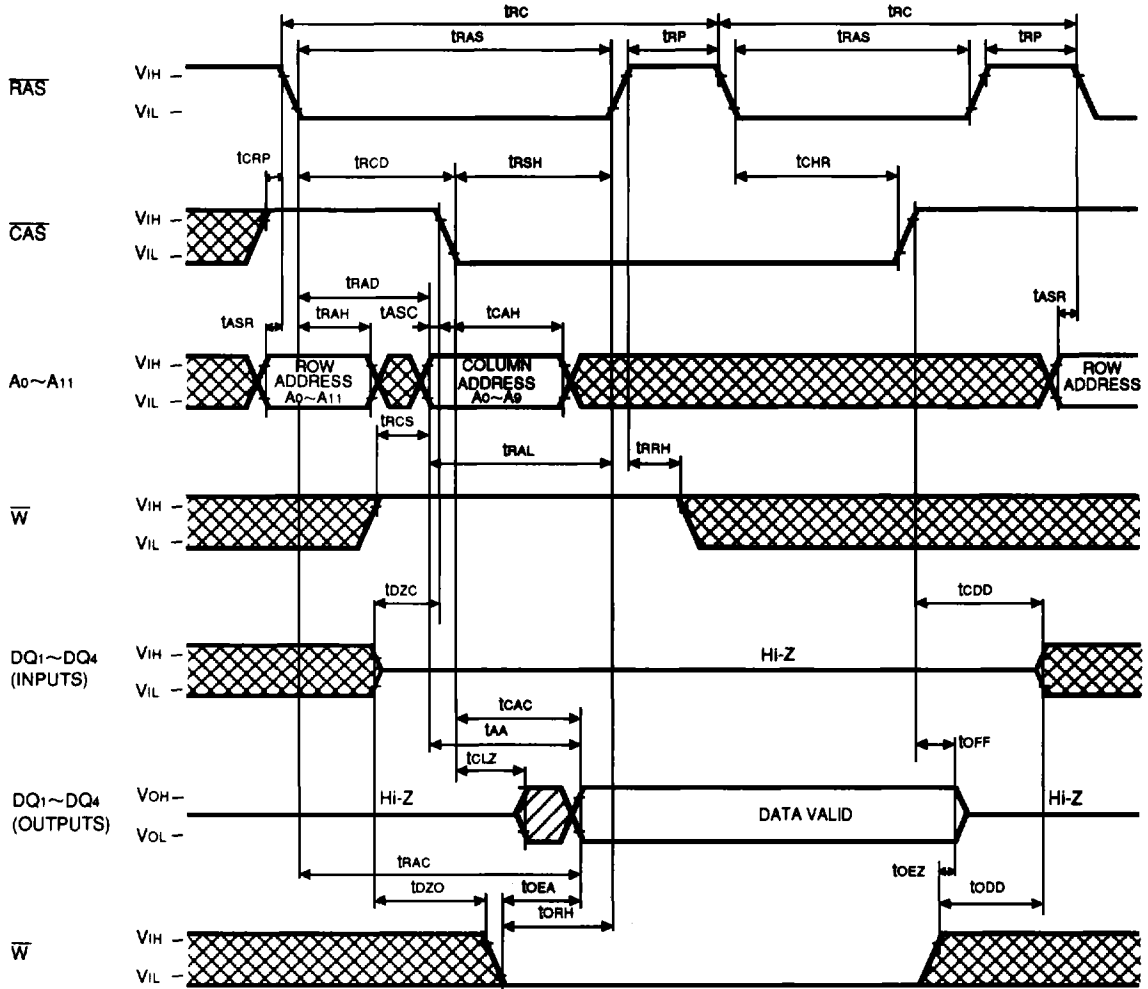
CAS before RAS Refresh Cycle



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Hidden Refresh Cycle (Read) (Note 28)

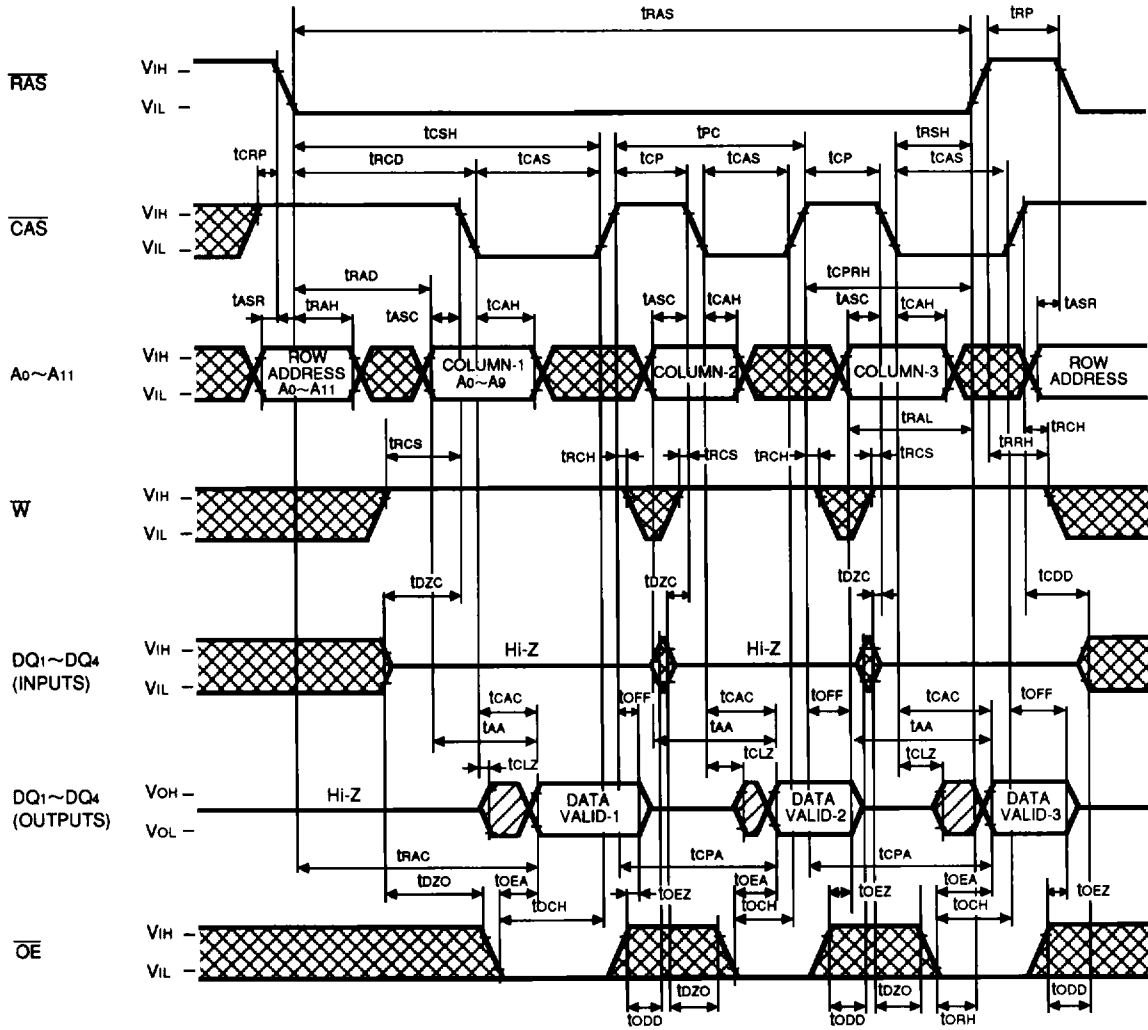


Note 28: Early write, delayed write, read write or read modify write cycle is applicable instead of read cycle. Timing requirements and output state are the same as that of each cycle shown above.

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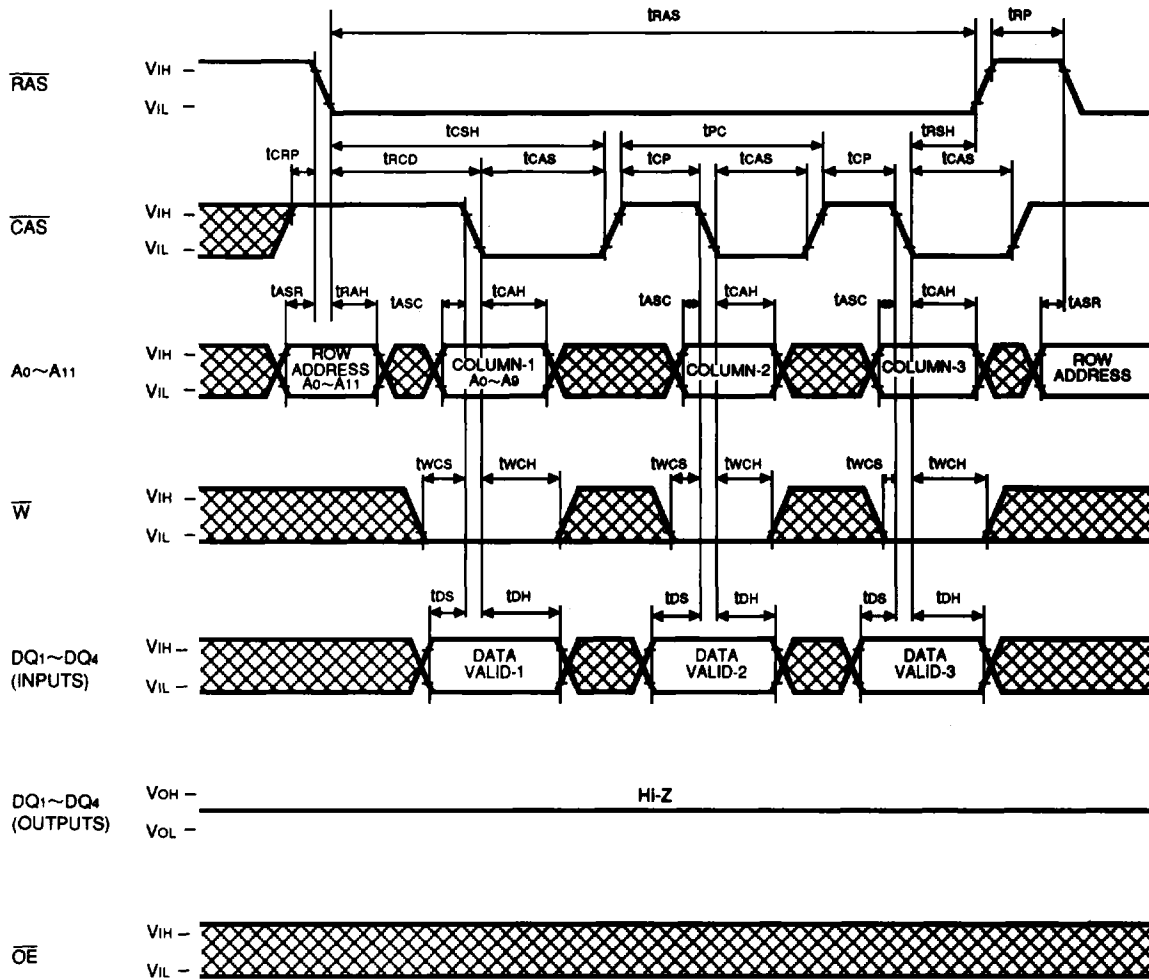
Fast Page Mode Read Cycle



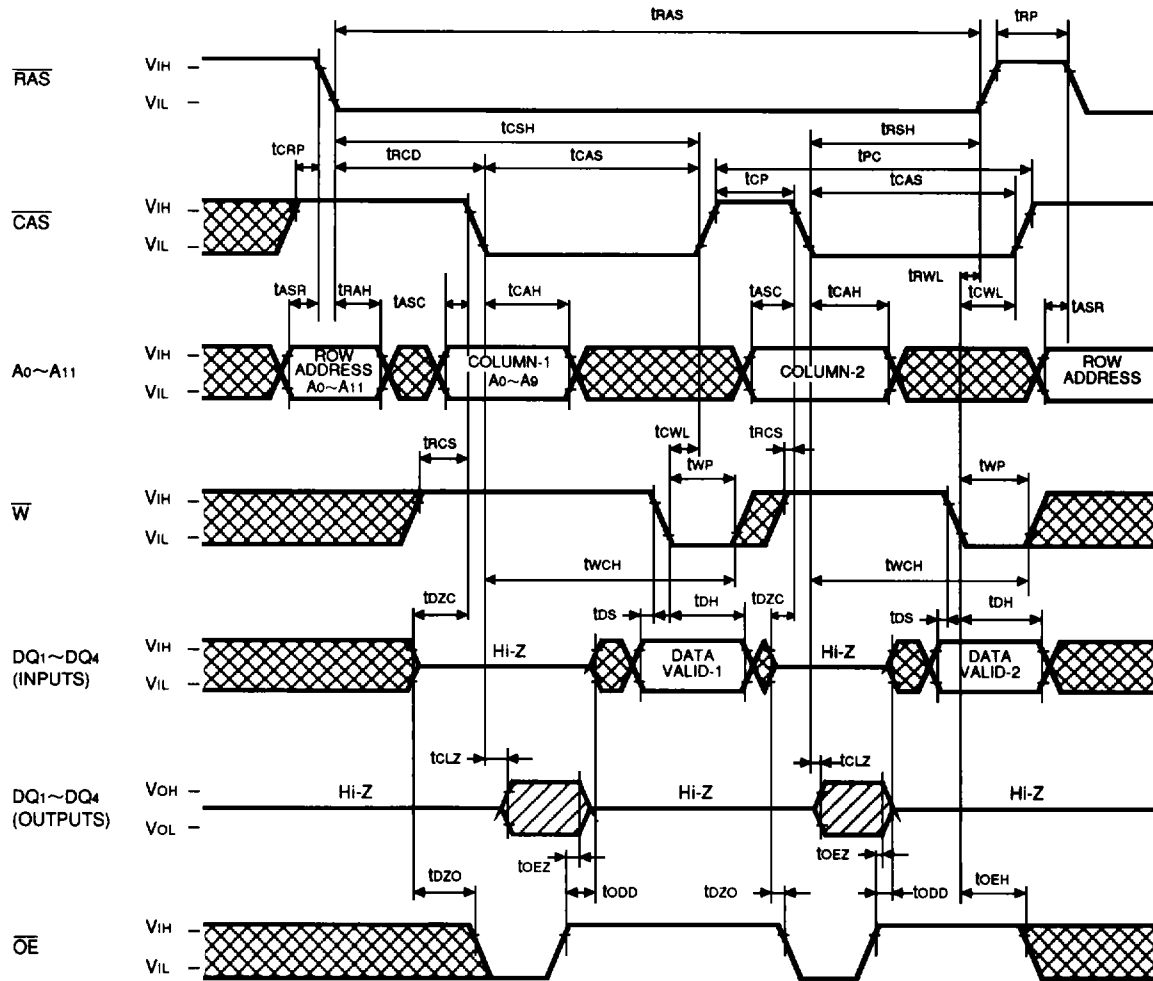
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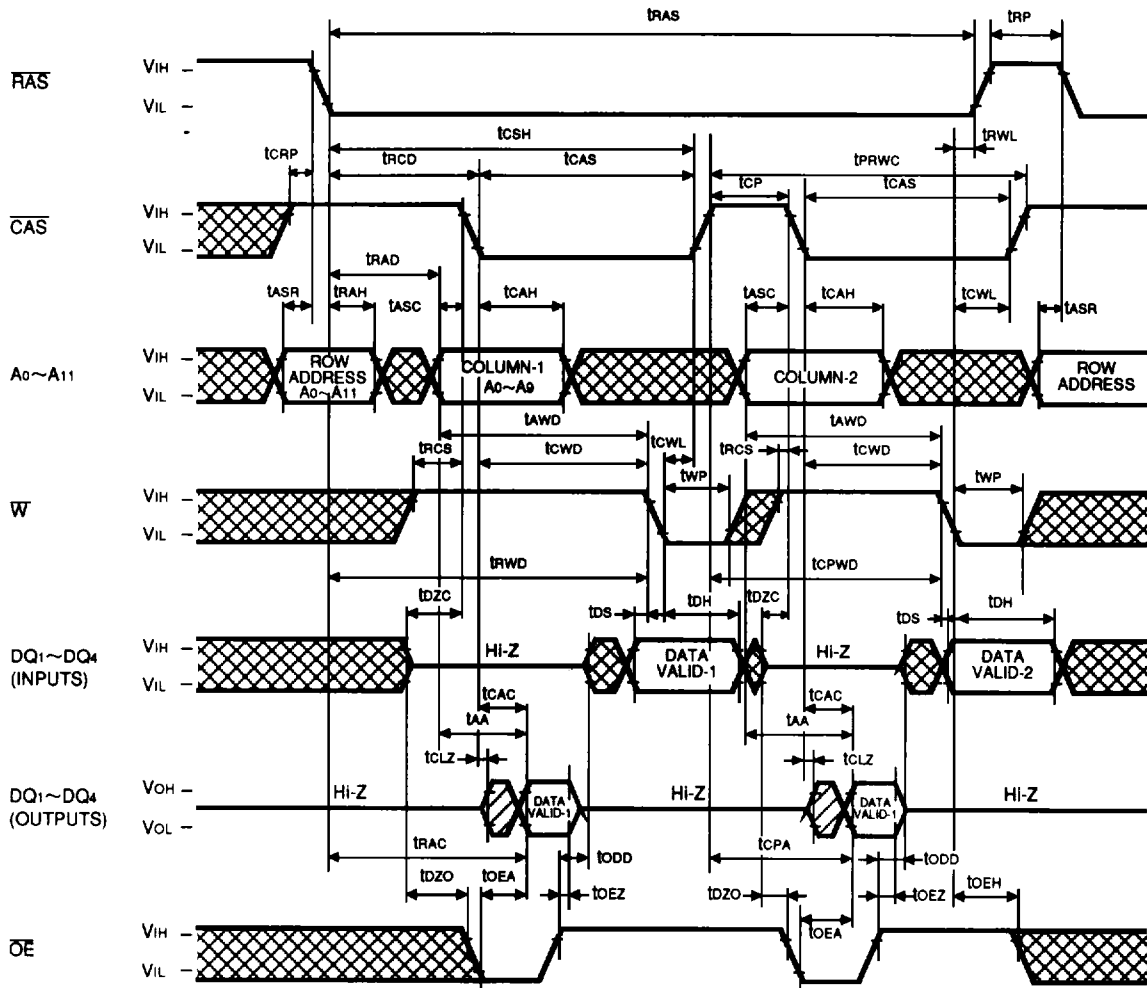
Fast Page Mode Write Cycle (Early Write)



Fast-Page Mode Write Cycle (Delayed Write)



Fast Page Mode Read-Write, Read-Modify-Write Cycle



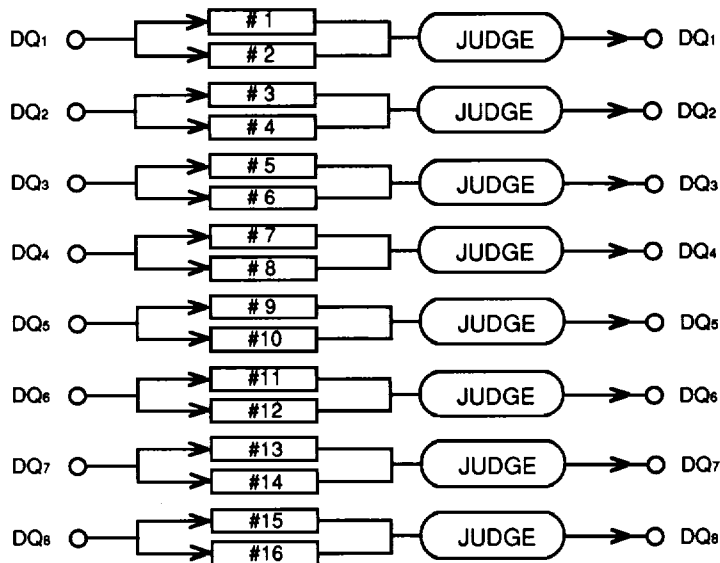
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TEST Mode SET Cycle

Symbol	Parameter	Limits				Unit
		M5M417800A-6,-6S		M5M417800A-7,-7S		
		Min	Max	Min	Max	
t _{WSR}	W setup time before RAS low	10		10		ns
t _{WHR}	W hold time after RAS low	10		15		ns

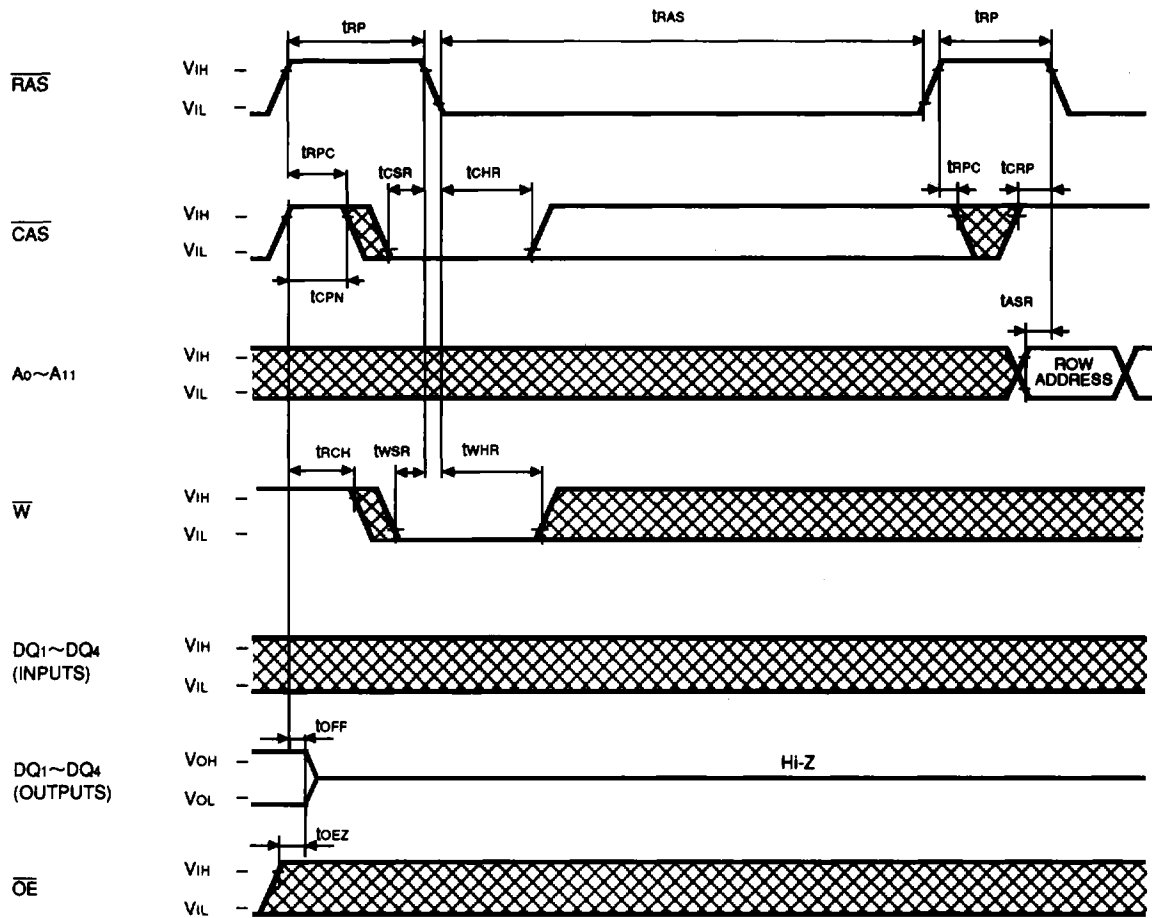
Note 29 : The test mode function is initiated by a **W** and **CAS** before **RAS** cycle (WCBR cycle) as specified in timing diagram. The test mode function is terminated by either a **CAS** before **RAS** refresh cycle (CBR refresh cycle) or a **RAS** only refresh cycle. During the test mode, the device is internally organized as 16 bits wide (1M bytes depth). No addressing of CA0, CA1 is required. During a write cycle, data must be applied to all DQ (input) pins. The data can be different between DQ pins. The data on each DQ pin is written into 2 bits memory cells, respectively. During a read cycle, each DQ (output) pin shows the test result of the 2 bits, respectively. High state indicates that they are same. Low state indicates that they are not same. During the test mode operation, WCBR cycle can be used to perform refresh.



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TEST Mode SET Cycle



SELF REFRESH SPECIFICATIONS

Self refresh devices are denoted by "S" after speed item, like -6S / -7S. The other characteristics and requirements than the below are same as normal devices.

ELECTRICAL CHARACTERISTICS (Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
I _{CCS} (AV)	Average supply current from V _{CC} Self-Refresh cycle	M5M417800A (S) FAS = CAS ≤ 0.2V			400	μA

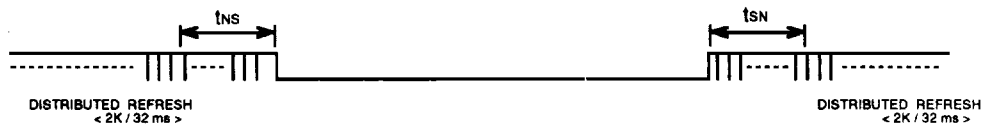
TIMING REQUIREMENTS (Ta = 0~70°C, Vcc = 5V±10%, Vss = 0V, unless otherwise noted See notes 12,13)

Symbol	Parameter	Limits				Unit
		M5M417800A-6S		M5M417800A-7S		
		Min	Max	Min	Max	
TRASS	Self Refresh FAS low pulse width	100		100		μs
TRPS	Self Refresh FAS high precharge time	110		130		ns
TCHS	Self Refresh FAS hold time	-50		-50		ns
TRSR	Read setup time before FAS low	10		10		ns
TRHR	Read hold time after FAS low	10		15		ns

SELF REFRESH ENTRY & EXIT CONDITIONS

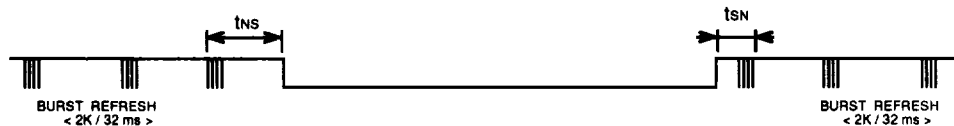
(1) In case of distributed refresh

The last / first full refresh cycles (2K) must be made within t_{NS} / t_{SN} before / after self refresh, on the condition of t_{NS} ≤ 32 ms and t_{SN} ≤ 32 ms.



(2) In case of burst refresh

The last / first full refresh cycles (2K) must be made within t_{NS} / t_{SN} before / after self refresh, on the condition of t_{NS} + t_{SN} ≤ 32 ms.



MITSUBISHI LSI
M5M417800AJ, TP-6,-7,-6S,-7S

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Self Refresh Cycle

